INTERNATIONAL STANDARD

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Second edition
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Superconductivity –

Part 3:
Critical current measurement –
DC critical current of Ag- and/or Ag alloy-sheathed Bi-2212 and Bi-2223 oxide superconductors

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CONTENTS

FOREWORD 3
INTRODUCTION 5

1 Scope 6
2 Normative reference 6
3 Terms and definitions 6
4 Principle 8
5 Requirements 8
6 Apparatus 8
7 Specimen preparation 9
8 Measurement procedure 10
9 Precision and accuracy of the test method 11
10 Calculation of results 12
11 Test report 13

Annex A (informative) Additional information relating to Clauses 1 to 10 15
Annex B (informative) Magnetic hysteresis of the critical current of high-temperature oxide superconductors 21

Bibliography 23

Figure 1 – Intrinsic *U-I* characteristic 14
Figure 2 – *U-I* characteristic with a current transfer component 14
Figure A.1 – Illustration of a measurement configuration for a short specimen of a few hundred A class conductors 20
Figure A.2 – Illustration of superconductor simulator circuit 20

Table A.1 – Thermal expansion data of Bi-oxide superconductor and selected materials 19

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SUPERCONDUCTIVITY –

Part 3: Critical current measurement – DC critical current of Ag- and/or Ag alloy-sheathed Bi-2212 and Bi-2223 oxide superconductors

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International Standard IEC 61788-3 has been prepared by IEC technical committee 90: Superconductivity.

This second edition cancels and replaces the first edition published in 2000. Modifications made to the second version mostly involve wording and essentially include no technical changes. Examples of technical changes introduced include the voltage lead diameter being smaller than 0,21 mm and the mode of expression for magnetic field accuracy being ±1 % and ±0,02 T instead of 1 %. The expression for magnetic field precision has been changed in the same way.

The text of this standard is based on the following documents:

FDIS	Report on voting
90/184/FDIS	90/190/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

IEC 61788 consists of the following parts, under the general title *Superconductivity*:

Part 1: Critical current measurement – DC critical current of Cu/Nb-Ti composite superconductors

Part 2: Critical current measurement – DC critical current of Nb_3Sn composite superconductors

Part 3: Critical current measurement – DC critical current of Ag- and/or Ag alloy-sheathed Bi-2212 and Bi-2223 oxide superconductors

Part 4: Residual resistance ratio measurement – Residual resistance ratio of Nb-Ti composite superconductors

Part 5: Matrix to superconductor volume ratio measurement – Copper to superconductor volume ratio of Cu/Nb-Ti composite superconductors

Part 6: Mechanical properties measurement – Room temperature tensile test of Cu/Nb-Ti composite superconductors

Part 7: Electronic characteristic measurements – Surface resistance of superconductors at microwave frequencies

Part 8: AC loss measurements – Total AC loss measurement of Cu/Nb-Ti composite superconducting wires exposed to a transverse alternating magnetic field by a pickup coil method

Part 9: Measurements for bulk high temperature superconductors – Trapped flux density of large grain oxide superconductors

Part 10: Critical temperature measurement – Critical temperature of Nb-Ti, Nb_3Sn, and Bi-system oxide composite superconductors by a resistance method

Part 11: Residual resistance ratio measurement – Residual resistance ratio of Nb_3Sn composite superconductors

Part 12: Matrix to superconductor volume ratio measurement – Copper to non-copper volume ratio of Nb_3Sn composite superconducting wires

Part 13: AC loss measurements – Magnetometer methods for hysteresis loss in Cu/Nb-Ti multifilamentary composites

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

INTRODUCTION

In 1986 J.G. Bednorz and K.A. Mueller discovered that some Perovskite type Cu-containing oxides show superconductivity at temperatures far above those which metallic superconductors have shown. Since then, extensive R & D work on high-temperature oxide superconductors has been and is being made worldwide, and its application to high-field magnet machines, low-loss power transmission, electronics and many other technologies is in progress [1].[1)]

Fabrication technology is essential to the application of high-temperature oxide superconductors. Among high-temperature oxide superconductors developed so far, BiSrCaCu oxide (Bi-2212 and Bi-2223) superconductors have been the most successful at being fabricated into wires and tapes of practical length and superconducting properties. These conductors can be wound into a magnet to generate a magnetic field of several tesla [2]. It has also been shown that Bi-2212 and Bi-2223 conductors can substantially raise the limit of magnetic field generation by a superconducting magnet [3].

In summer 1993, VAMAS-TWA16 started working on the test methods of critical currents in Bi-oxide superconductors. In September 1997, the TWA16 worked out a guideline (VAMAS guideline) on the critical current measurement method for Ag-sheathed Bi-2212 and Bi-2223 oxide superconductors. This pre-standardization work of VAMAS was taken as the base for the IEC standard, described in the present document, on the dc critical current test method of Ag-sheathed Bi-2212 and Bi-2223 oxide superconductors.

The test method covered in this International Standard is intended to give an appropriate and agreeable technical base to those engineers working in the field of superconductivity technology.

The critical current of composite superconductors like Ag-sheathed Bi-oxide superconductors depends on many variables. These variables need to be considered in both the testing and the application of these materials. Test conditions such as magnetic field, temperature and relative orientation of the specimen and magnetic field are determined by the particular application. The test configuration may be determined by the particular conductor through certain tolerances. The specific critical current criterion may be determined by the particular application. It may be appropriate to measure a number of test specimens if there are irregularities in testing.

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1) The numbers in brackets refer to the bibliography.

SUPERCONDUCTIVITY –

Part 3: Critical current measurement – DC critical current of Ag- and/or Ag alloy-sheathed Bi-2212 and Bi-2223 oxide superconductors

1 Scope

This part of IEC 61788 covers a test method for the determination of the dc critical current of short and straight Ag- and/or Ag alloy-sheathed Bi-2212 and Bi-2223 oxide superconductors that have a monolithic structure and a shape of round wire or flat or square tape containing mono- or multicores of oxides.

This method is intended for use with superconductors that have critical currents less than 500 A and *n*-values larger than 5. The test is carried out with and without an applying external magnetic field. For all tests in a magnetic field, the magnetic field is perpendicular to the length of the specimen. In the test of a tape specimen in a magnetic field, the magnetic field is parallel or perpendicular to the wider tape surface (or one surface if square). The test specimen is immersed either in a liquid helium bath or a liquid nitrogen bath during testing. Deviations from this test method that are allowed for routine tests and other specific restrictions are given in this standard.

2 Normative reference

The following referenced document is indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-815:2000, *International Electrotechnical Vocabulary (IEV) – Part 815: Superconductivity*